

TECHNICAL SPEC FOR CD-SEM

System Model:

Hitachi S-9220

Tool was operational at shutdown, and was being brought up in 2024 for 8 inch GaN measurements.

Wafer size: 6 inch

Cassette to Cassette: Yes

Robot:

Measuring size:

SECS/GEM: yes

Voltage: typ 800V

Layout: see pictures

Measuring range: 0.1 um upwards

Image magnification: 150kx

Optical microscope image: yes

Automatic measurement: yes

Loader system: autoloader system

Wafer detection in cassette: yes

Vintage: 2000

Missing/defective parts: none

